PAST TTTC EVENTS
IEEE International Symposium on Defect and Fault Tolerance in VLSI Systems (DFT 2009)
7–9 October 2009
Chicago, Illinois
http://www.dfts.org/index.html

DFT is an annual symposium providing an open forum for presentations in the field of defect and fault tolerance in VLSI systems including emerging technologies. One of the symposium’s unique features is that new academic research is combined with state-of-the-art industrial data, necessary ingredients for significant advances in this field. All aspects of design, manufacturing, test, reliability, and availability that are affected by defects during manufacturing, and by faults during system operation, are of interest.

DFT 2009 was well attended. The program included four keynotes, six invited talks, and approximately 50 papers and posters in addition to a panel. The keynote speakers were Michael Campbell of Qualcomm, Sandeep P. Kumar of Silicon Laboratories, Naveed Sherwani, president and CEO of Open Silicon, and Norman P. Jouppi, HP Fellow and director of Exascale Computing Laboratory from Hewlett-Packard Laboratories.

UPCOMING TTTC EVENTS
13th Design, Automation, and Test in Europe (DATE 2010)
8–12 March 2010
Dresden, Germany
http://www.date-conference.com

DATE puts strong emphasis on ICs and SoCs, reconfigurable hardware, and embedded systems, including embedded software.

The five-day event consists of a conference with plenary invited papers, regular papers, panels, hot-topic sessions, tutorials, and workshops, two special focus days, and a track specifically for executives. The scientific conference is complemented by a commercial exhibition showing the state-of-the-art in design and test tools, methodologies, IP, and design services, reconfigurable and other hardware platforms, embedded software, and (industrial) design experiences from different application domains—for example, automotive, wireless, telecom, and multimedia applications. The organization of user group meetings, fringe meetings, a university booth, vendor presentations, and social events offers a wide variety of extra opportunities to meet and exchange information on relevant issues for the design and test community. Special space will also be allocated for EU-funded projects to show their results.

IEEE VLSI Test Symposium (VTS 2010)
18–21 April 2009
Santa Cruz, California

The IEEE VLSI Test Symposium (VTS) explores emerging trends and novel concepts in testing, verification and validation of microelectronic circuits and systems few of which are analog and RF circuits, digital circuits, FPGAs, embedded systems, and memory. In addition to the high-quality papers presented in VTS, the Innovative Practices track and Special Sessions are very popular among researchers from both academia and industry. The innovative practices track will highlight cutting-edge challenges faced by test practitioners, and innovative solutions employed to address them. Special sessions can include panels, embedded tutorials, or hot topic presentations.
CALL FOR PAPERS
International Test Conference (ITC 2010)
Submission deadline: February 2010
http://www.itctestweek.org/

The International Test Conference is the world’s premier conference dedicated to the electronic test of devices, boards, and systems, covering the complete cycle—from design verification, test, diagnosis, failure analysis, back to process and design improvement. At ITC, test and design professionals can confront the challenges the industry faces, and learn how these challenges are being addressed by the combined efforts of academia, design tool and equipment suppliers, designers, and test engineers.

NEWSLETTER EDITOR’S INVITATION
I would appreciate input and suggestions about the newsletter from the test community. Please forward your ideas; contributions; and information on awards, conferences, and workshops to Mohammad Tehranipoor, Electrical and Computer Engineering Department, Univ. of Connecticut, 371 Fairfield Way, Storrs, CT 06269-2157; tehrani@engr.uconn.edu.

Mohammad Tehranipoor
Editor, TTTC Newsletter

CONTRIBUTIONS TO THIS NEWSLETTER: Send contributions to Mohammad Tehranipoor, Electrical and Computer Engineering Department, Univ. of Connecticut, 371 Fairfield Way, Storrs, CT 06269-2157; tehrani@engr.uconn.edu. For more information, see the TTTC Web page: http://tab.computer.org/tttc.